



18. TEST PHOTOGRAPHS

See following Attached Pages for setup photographs.

FCC ID: A3LSMJ530G	 PCTEST ENGINEERING LABORATORY, INC.	HAC (RF EMISSIONS) TEST REPORT		Approved by: Quality Manager
Filename: 1M1704110140-11.A3L	Test Dates: 03/27/2017 - 04/03/2017	DUT Type: Portable Handset	Page 79 of 81	

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Figure 18-1
Ear Reference Point HAC Phantom Alignment

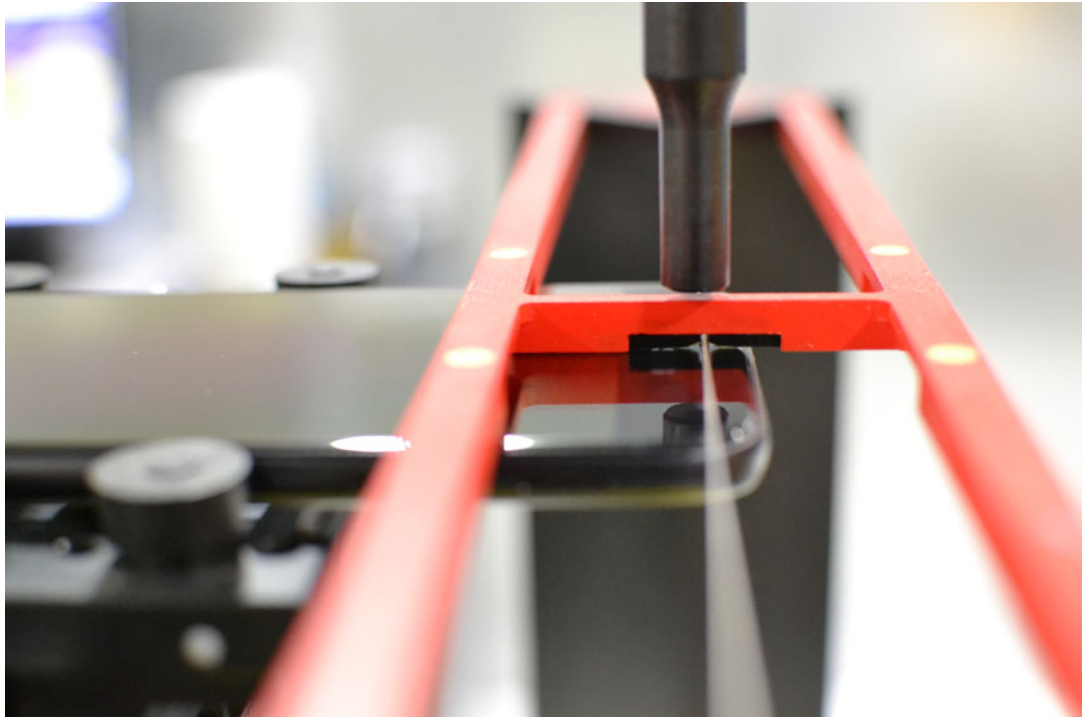




Figure 18-2
HAC Phantom Plane Alignment

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03/24/2017

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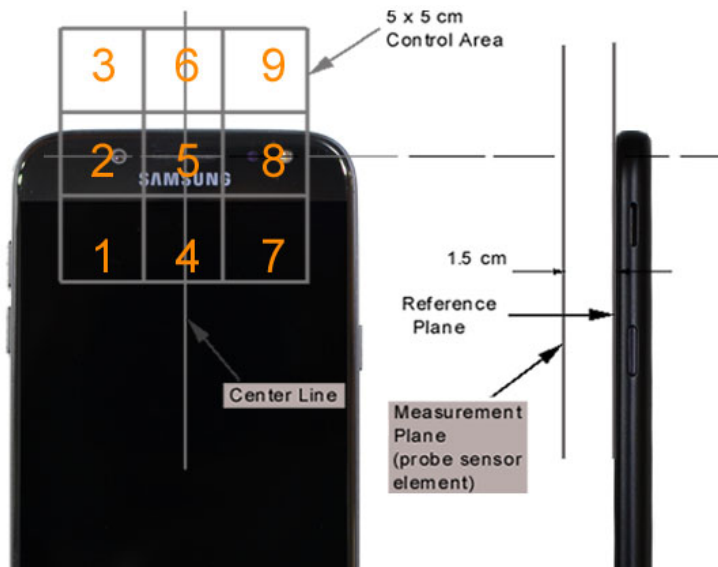




Figure 18-3 5x5 Scan grid above WD



Figure 18-4 E-Field WD Scan overlay

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